

<b>Notice of References Cited</b>		Application/Control No. 10/777,918	Applicant(s)/Patent Under Reexamination D'HERS ET AL.	
		Examiner SCOTT L. JARRETT	Art Unit 3624	Page 1 of 1

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*	C US-6,732,115	05-2004	Shah et al.	707/102
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.